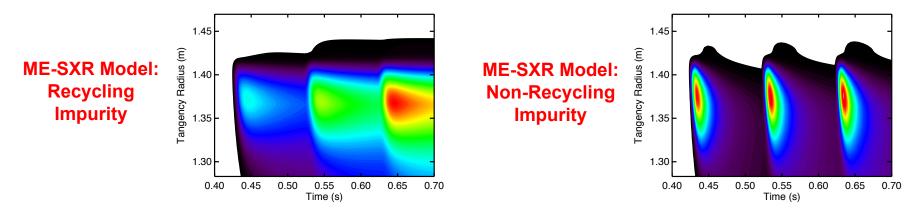
Direct Perturbative Transport Measurements with Proposed Diagnostics D. Clayton for the JHU Plasma Spectroscopy Group

- Laser ablation provides a well-defined, non-recycling impurity source
 - Better-constrained impurity source provides more accurate transport measurements
 - Short (1-2 ms) pulses of fast (a few eV) neutral atoms (~10¹⁷ particles per pulse, variable)
 - Injected source is monitored by a filtered diode
 - Impurities are non-recycling, removing additional source terms from model
 - Wider variety of impurities to choose from (C, Mo, non-intrinsic materials)
 - Multiple transport measurements per discharge (less impurity accumulation)
 - Laser ablation can also provide cold pulses for electron heat transport
- New ME-SXR arrays will cover the core as well as the edge plasma
 - Fast (~10-100 kHz) emission measurements for impurity transport
 - Fast *T_e* measurements between Thomson pulses for heat transport
- Upgraded TGIS will provide faster time resolution (5-10 ms) impurity profiles
 - Assists ME-SXR temperature modeling

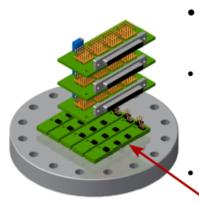


Backup Slides

JHU Diagnostics for SFPS research 2014-2018 - K. Tritz - 09/1/2011

Toroidally Displaced In-vessel ME-SXR arrays

K. Tritz for the JHU Plasma Spectroscopy Group



We propose a system of two toroidally displaced, tangential edge/core multi-energy SXR (ME-SXR) arrays

Each array contains:

- edge sub-array (130<R<150) ~1cm resolution, 5 diode arrays @ 20ch. ea.
- core sub-array (40<R<140) ~3cm resolution, 3 diode arrays @ 32ch ea.
- time resolution 10-100kHz

In-vessel design reduces port crowding, increases placement flexibility

- design 1: electronics in re-entrant can @ atmosphere with air cooling
- design 2: vacuum compatible first stage electronics on detector PCB
- potential to incorporate A/D, (fiber?) serial output for reduced wire count

Projected physics capabilities for NSTX-U:

- impurity/electron perturbative transport measurements from the edge to the core using gas puff and repetitive laser blow-off
- fast, high resolution edge T_e , n_e , and n_z profiles for ELM studies and code validation; edge stability analysis
- fast, toroidally resolved edge T_e , n_e , and n_z profiles for RWM/RFA studies
- fast, toroidally resolved core T_e , n_e , and n_z profiles for disruption studies
- real-time T_e measurements for stability prediction and feedback control development
- enhanced, non-magnetic MHD mode identification

Supports NSTX-U research priorities:

- I-1-4: macrostability research of RWMs, NTMs, effect of 3D fields, disruptions
- II-3: impurity transport research (also pert. electron transport measurements)
- III-3: measure response of edge plasma to applied 3D fields
- VI-1,2: real-time T_e for stability feedback control, detection of instability precursors

Fast Transmission Grating Imaging Spectrometer (TGIS) for NSTX-UD. Stutman for the Johns Hopkins Group

• Fast tangential TGIS for space-resolved XUV (50-800 Å) impurity spectra:

- Space/time resolved impurity fractions for improved ME-SXR modeling

- Low to high-Z impurity monitoring for start-up to non-inductive sustainment

- Stand-alone' impurity transport (V pinch)

- Parameters: $\ge 2 \text{ cm}/5-10 \text{ ms space/time resolution}, 90 \le R \le 150 \text{ cm}$
 - Beam view for low-Z /CX , high-Z /electron-excited spectra
 - Enhanced Mo detection capability
 - V12V Addresses II 2 III 2 plasma **Region of intense** plasma axis beam emission 666 4 axis - 630 A : O V + O VIIL **Transmission Grating** - 521 A : C VI4-3 Imaging Spectrometer Traces of CI -- 415 A : CI XV - 384 A : CI XV - 364 A : 2 x 182 A Fe, Cr **Traces of Fe** - 335 A: Fe XVI - 293 A : 0 VIII₄₋₃ - 268 A : 2 x 135 A accumulation (few 10⁻⁴xn_o) - 237 A : CI XIV = 200 A : 2 × 100 A = 182 A : C VL Bright CX signals - 135 A : C VI4.2 + Li2.1 + NVII3.2? from Li, C, N, O - 102 A : 3 x 34 A + O VIIL -

Low P_{rad} NBI plasma

High P_{rad} NBI plasma

SXR/VUV Imaging Radiometer for NSTX-U divertor

D. Stutman for the Johns Hopkins Group

• Space/time resolved radiated power in $\lambda/\Delta\lambda \sim 1/20$ spectral bins covering the 0-150 Å ('SXR') and 0-1500 Å ('VUV) ranges

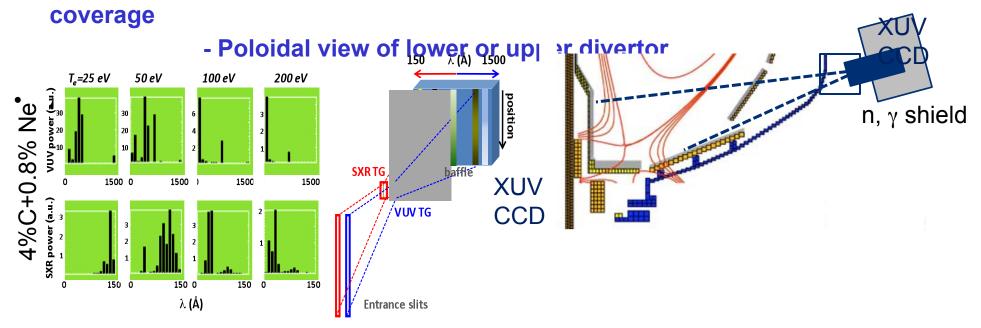
- $\textbf{P}_{\text{rad}}(\lambda),$ impurity type, charge state distribution for enhanced constraints on

divertor modeling (M. Jaworski)

- Approximate line-of-sight T_e (with e.g., Neon seeding)

• Parameters: - Dual transmission grating + absolute XUV CCD for $P_{rad}(\lambda)$

- ≥2 cm/5-10ms space/time resolution, strike to above X-point



Repetitive Laser Blow-off Impurity Injection System D. Clayton for the JHU Plasma Spectroscopy Group

- We propose a repetitive laser blow-off impurity injection system for transport measurements of non-recycling impurities
 - Laser with \geq 10 Hz rep rate, 100's of mJ per pulse, scans target throughout discharge
 - Based on C-Mod system, cost within scope of a university collaboration
 - Impurity transport measurements will be made with JHU's proposed in-vessel ME-SXR arrays and fast TGIS diagnostics
 - Other possible uses include T_e transport measurements via cold pulse propagation
- Benefits of laser ablation of non-recycling impurities include:
 - More NSTX-relevant impurities (Li, C, Mo, etc.)
 - Better-constrained impurity source term for transport modeling
 - Multiple transport measurements per discharge (less impurity accumulation)
- Reflex discharge plasma will be used to characterize impurity injection
 - Simulate SOL conditions to determine source term and test STRAHL SOL model

